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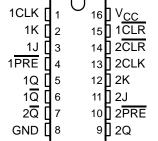
 Package Options Include Plastic Small-Outline (D) and Ceramic Flat (W)
 Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J)
 300-mil DIPs

#### description

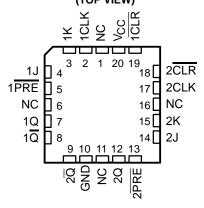
The 'HC112 contain two independent J-K negative-edge-triggered flip-flops. A low level at the preset (PRE) or clear (CLR) inputs sets or resets the outputs regardless of the levels of the other inputs. When PRE and CLR are inactive (high), data at the J and K inputs meeting the setup time requirements are transferred to the outputs on the negative-going edge of the clock (CLK) pulse. Clock triggering occurs at a voltage level and is not directly related to the rise time of CLK. Following the hold-time interval, data at the J and K inputs may be changed without affecting the levels at the outputs. These versatile flip-flops perform as toggle flip-flops by tying J and K high.

The SN54HC112 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74HC112 is characterized for operation from -40°C to 85°C.

## SN54HC112...J OR W PACKAGE SN74HC112...D OR N PACKAGE (TOP VIEW)



# SN54HC112 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

#### **FUNCTION TABLE**

		INPUTS			OUTI	PUTS
PRE	CLR	CLK	J	K	Q	Q
L	Н	Х	Х	Х	Н	L
Н	L	X	Χ	X	L	Н
L	L	X	Χ	X	H <sup>†</sup>	H <sup>†</sup>
Н	Н	$\downarrow$	L	L	Q <sub>0</sub>	$\overline{Q}_0$
н	Н	$\downarrow$	Н	L	Н	L
Н	Н	$\downarrow$	L	Н	L	Н
Н	Н	$\downarrow$	Н	Н	Тод	gle
Н	Н	Н	Χ	Х	Q <sub>0</sub>	$\overline{Q}_0$

<sup>†</sup> This configuration is unstable; that is, it does not persist when either PRE or CLR returns to its inactive (high) level.

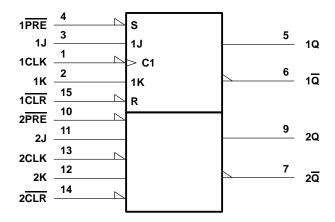


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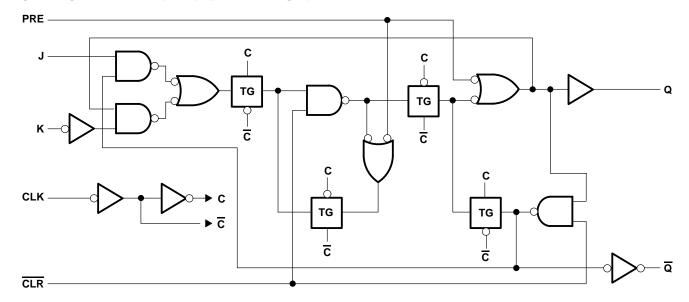
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#### logic symbol<sup>†</sup>



<sup>&</sup>lt;sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, J, N, and W packages.

#### logic diagram, each flip-flop (positive logic)





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#### absolute maximum ratings over operating free-air temperature range†

Supply voltage range, V <sub>CC</sub>	–0.5 V to 7 V
Input clamp current, $I_{IK}$ ( $V_I < 0$ or $V_I > V_{CC}$ ) (see Note 1)	±20 mA
Output clamp current, I <sub>OK</sub> (V <sub>O</sub> < 0 or V <sub>O</sub> > V <sub>CC</sub> ) (see Note 1)	±20 mA
Continuous output current, $I_O$ ( $V_O = 0$ to $V_{CC}$ )	±25 mA
Continuous current through V <sub>CC</sub> or GND	±50 mA
Package thermal impedance, θ <sub>JA</sub> (see Note 2): D package	113°C/W
N package	
Storage temperature range, T <sub>stq</sub>	–65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

#### recommended operating conditions

			SI	154HC11	2	18	SN74HC112		UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	UNII
Vсс	Supply voltage		2	5	6	2	5	6	V
		V <sub>CC</sub> = 2 V	1.5			1.5			
٧ıH	High-level input voltage	$V_{CC} = 4.5 \text{ V}$	3.15			3.15			V
		V <sub>CC</sub> = 6 V	4.2			4.2			
		V <sub>CC</sub> = 2 V	0		0.5	0		0.5	
VIL	Low-level input voltage	V <sub>CC</sub> = 4.5 V	0		1.35	0		1.35	V
		VCC = 6 V	0		1.8	0		1.8	
٧ <sub>I</sub>	Input voltage		0		VCC	0		VCC	V
۷o	Output voltage		0		VCC	0		VCC	V
		V <sub>CC</sub> = 2 V	0		1000	0		1000	
t <sub>t</sub> ‡	Input transition (rise and fall) time	V <sub>CC</sub> = 4.5 V	0		500	0		500	ns
		V <sub>CC</sub> = 6 V	0		400	0		400	
TA	Operating free-air temperature		-55		125	-40		85	°C

If this device is used in the threshold region (from V<sub>IL</sub>max = 0.5 V to V<sub>IH</sub>min = 1.5 V), there is a potential to go into the wrong state from induced grounding, causing double clocking. Operating with the inputs at t<sub>t</sub> = 1000 ns and V<sub>CC</sub> = 2 V does not damage the device; however, functionally, the CLK inputs are not ensured while in the shift, count, or toggle operating modes.



<sup>2.</sup> The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

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# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CO	ONDITIONS	Vaa	Т	A = 25°C	;	SN54H	IC112	SN74H	C112	UNIT
PARAMETER	1231 CC	MDITIONS	vcc	MIN	TYP	MAX	MIN	MAX	MIN MAX  1.9  4.4  5.9  3.84  5.34  1 0.1 1 0.1 1 0.1 4 0.33 4 0.33 0 ±1000	OIVII	
			2 V	1.9	1.998		1.9		1.9		
		I <sub>OH</sub> = -20 μA	4.5 V	4.4	4.499		4.4		4.4		
Voн	VI = VIH or VIL		6 V	5.9	5.999		5.9		5.9		V
		$I_{OH} = -4 \text{ mA}$	4.5 V	3.98	4.3		3.7		3.84		
		$I_{OH} = -5.2 \text{ mA}$	6 V	5.48	5.8		5.2		5.34		
			2 V		0.002	0.1		0.1		0.1	
		$I_{OL} = 20  \mu A$	4.5 V		0.001	0.1		0.1		0.1	
VOL	VI = VIH or VIL		6 V		0.001	0.1		0.1		0.1	V
		I <sub>OL</sub> = 4 mA	4.5 V		0.17	0.26		0.4		0.33	
		$I_{OL} = 5.2 \text{ mA}$	6 V		0.15	0.26		0.4		0.33	
lį	$V_I = V_{CC}$ or 0		6 V		±0.1	±100		±1000		±1000	nA
ICC	$V_I = V_{CC}$ or 0,	I <sub>O</sub> = 0	6 V			4		80		40	μΑ
C <sub>i</sub>			2 V to 6 V		3	10		10		10	pF

# timing requirements over recommended operating free-air temperature range (unless otherwise noted)

			\ \ \	T <sub>A</sub> = :	25°C	SN54F	IC112	SN74H	IC112	LINIT
			Vcc	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
f <sub>clock</sub> Clock frequency			2 V	0	5	0	3.4	0	4	
		4.5 V	0	25	0	17	0	20	MHz	
			6 V	0	29	0	20	0	24	
t <sub>W</sub> Pulse duration		2 V	100		150		125			
	PRE or CLR low	4.5 V	20		30		25			
	Pulse duration		6 V	17		25		21		ns
		CLK high or low	2 V	100		150		125		
			4.5 V	20		30		25		
			6 V	17		25		21		
		Data (J, K)	2 V	100		150		125		ns
			4.5 V	20		30		25		
١.	Setup time before CLK↓		6 V	17		25		21		
t <sub>su</sub>	Setup time before CLK		2 V	100		150		125		
		PRE or CLR inactive	4.5 V	20		30		25		
			6 V	17		25		21		
			2 V	0		0		0		ns
th	Hold time, data after $CLK\!\!\downarrow$		4.5 V	0		0		0		
			6 V	0	·	0		0		

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# switching characteristics over recommended operating free-air temperature range, $C_L$ = 50 pF (unless otherwise noted) (see Figure 1)

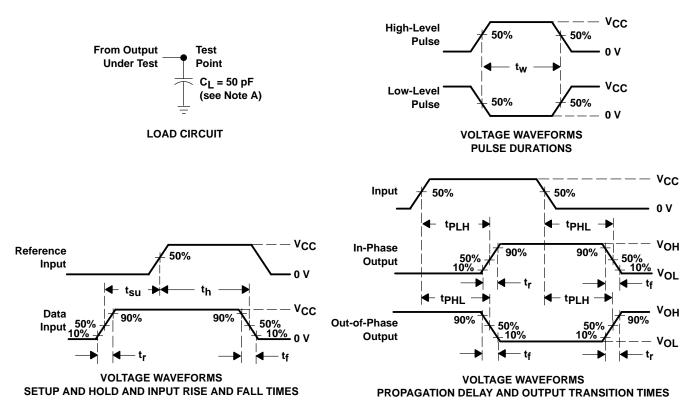
PARAMETER	FROM	то	V	T,	\ = 25°C	;	SN54H	IC112	SN74H	IC112	UNIT
PARAMETER	(INPUT)	(OUTPUT)	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII
			2 V	5	10		3.4		4		
f <sub>max</sub>			4.5 V	25	50		17		20		MHz
			6 V	29	60		20		24		
	PRE or CLR Q or Q		2 V		54	165		245		205	
		Q or $\overline{\mathbb{Q}}$	4.5 V		16	33		49		41	
<b>.</b>			6 V		13	28		42		35	20
<sup>t</sup> pd			2 V		56	125		185		155	ns
	CLK	Q or $\overline{Q}$	4.5 V		16	25		37		31	
			6 V		13	21		31		26	
			2 V		29	75		110		95	
t <sub>t</sub>		Q or $\overline{Q}$	4.5 V		9	15		22		19	ns
			6 V		8	13		19		16	

## operating characteristics, $T_A = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS	TYP	UNIT
C <sub>pd</sub>	Power dissipation capacitance per flip-flop	No load	35	pF

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#### PARAMETER MEASUREMENT INFORMATION



NOTES: A. C<sub>L</sub> includes probe and test-fixture capacitance.

- B. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_{\Omega} = 50 \Omega$ ,  $t_{r} = 6$  ns,  $t_{f} = 6$  ns.
- C. For clock inputs,  $f_{\mbox{max}}$  is measured when the input duty cycle is 50%.
- D. The outputs are measured one at a time with one input transition per measurement.
- E. tpLH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



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